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# Introduction of NTK & products

Feb. 6th, 2026

Niterra North America, Inc. (NTK CERATEC)



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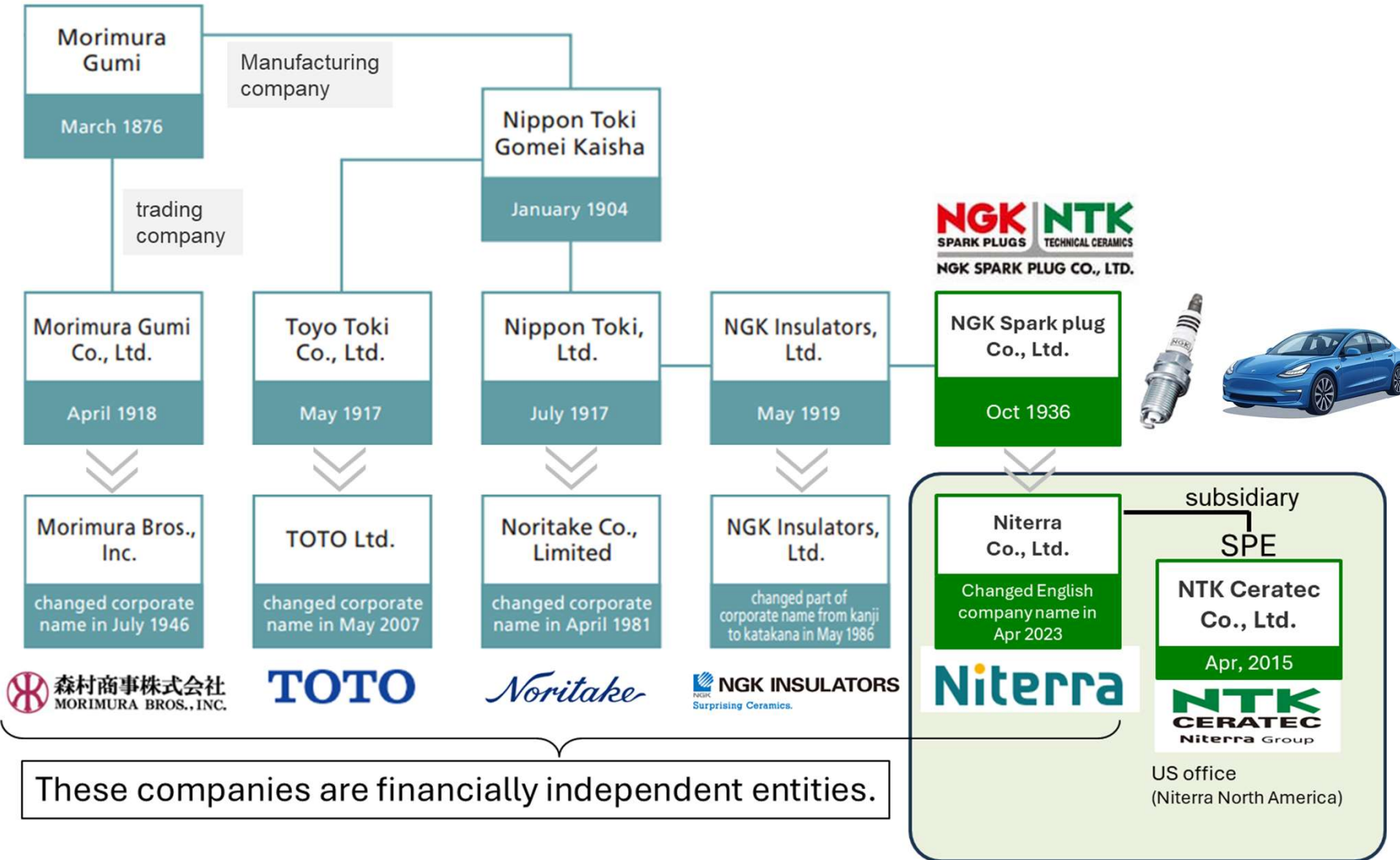
Challenge the  
*next*  
generation with  
ceramics!

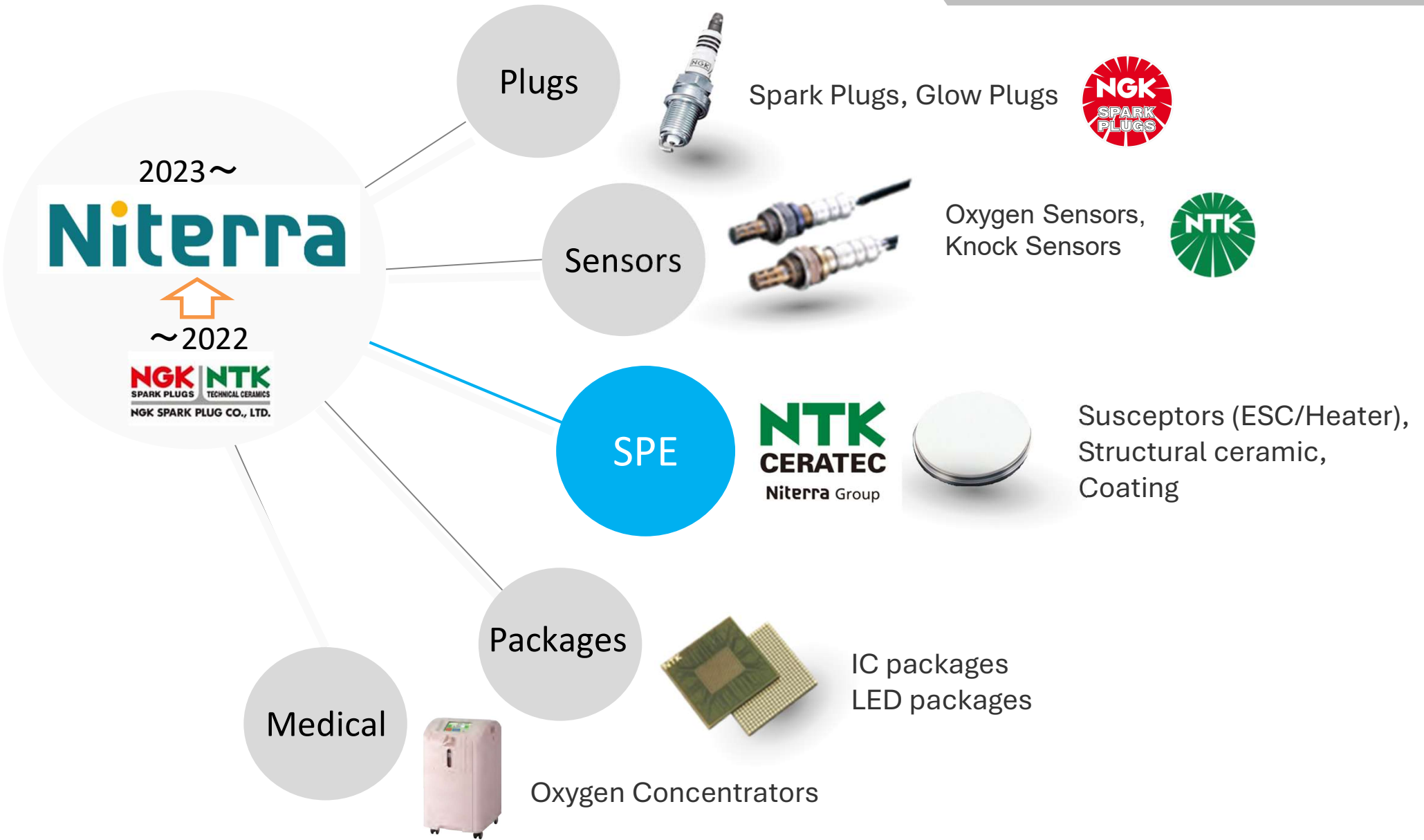
- ✓ Company profile
- ✓ Company highlights
- ✓ Key products

# Company profile



# Corporate History





# Company overview of NTK CERATEC



Establishment : 1987s  
HQ : Sendai city, Miyagi, Japan



797 (as of Apr 1st, 2025)



JPY 34,600M (March 2024) ≒ \$234M  
(\$1.00 = JPY147.00)



ISO9001 & ISO14001



Komaki factory  
Sendai 1<sup>st</sup> ~3<sup>rd</sup> factories  
YEEDEX CERATEC Corp. (Taiwan)



Tokyo sales office  
Niterra North America, Inc. (USA)

# Location Japan



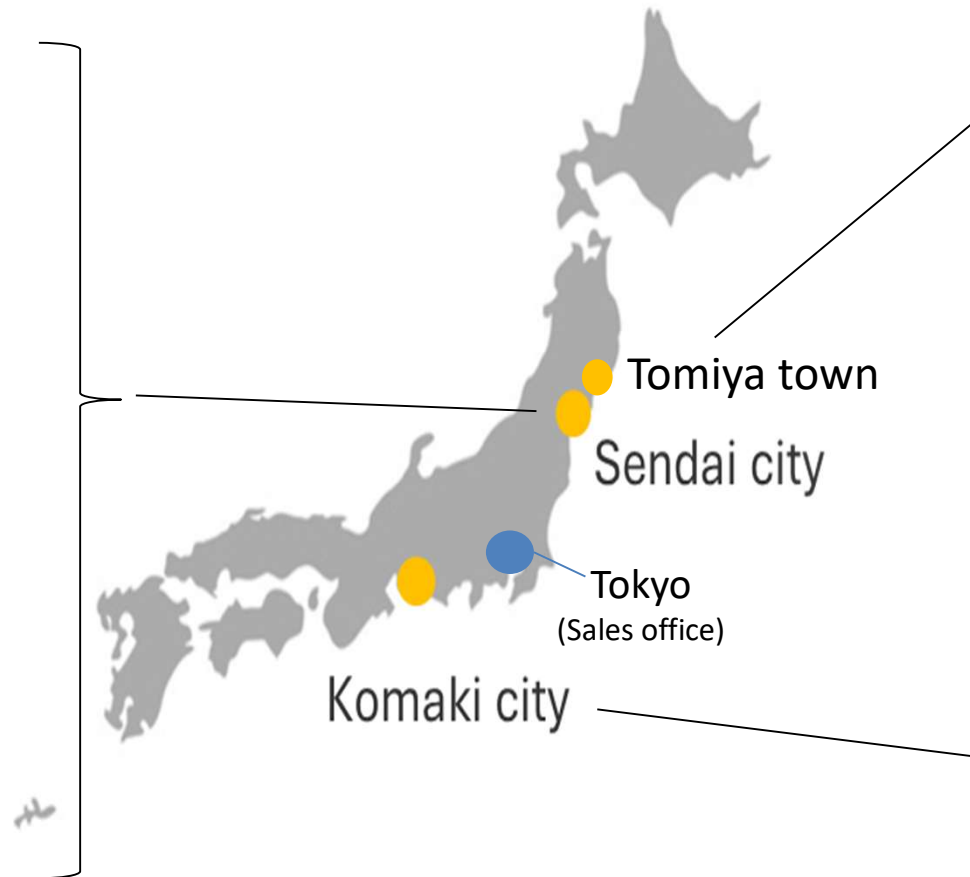
Headquarters Sendai



Sendai Fab1



Sendai Fab2

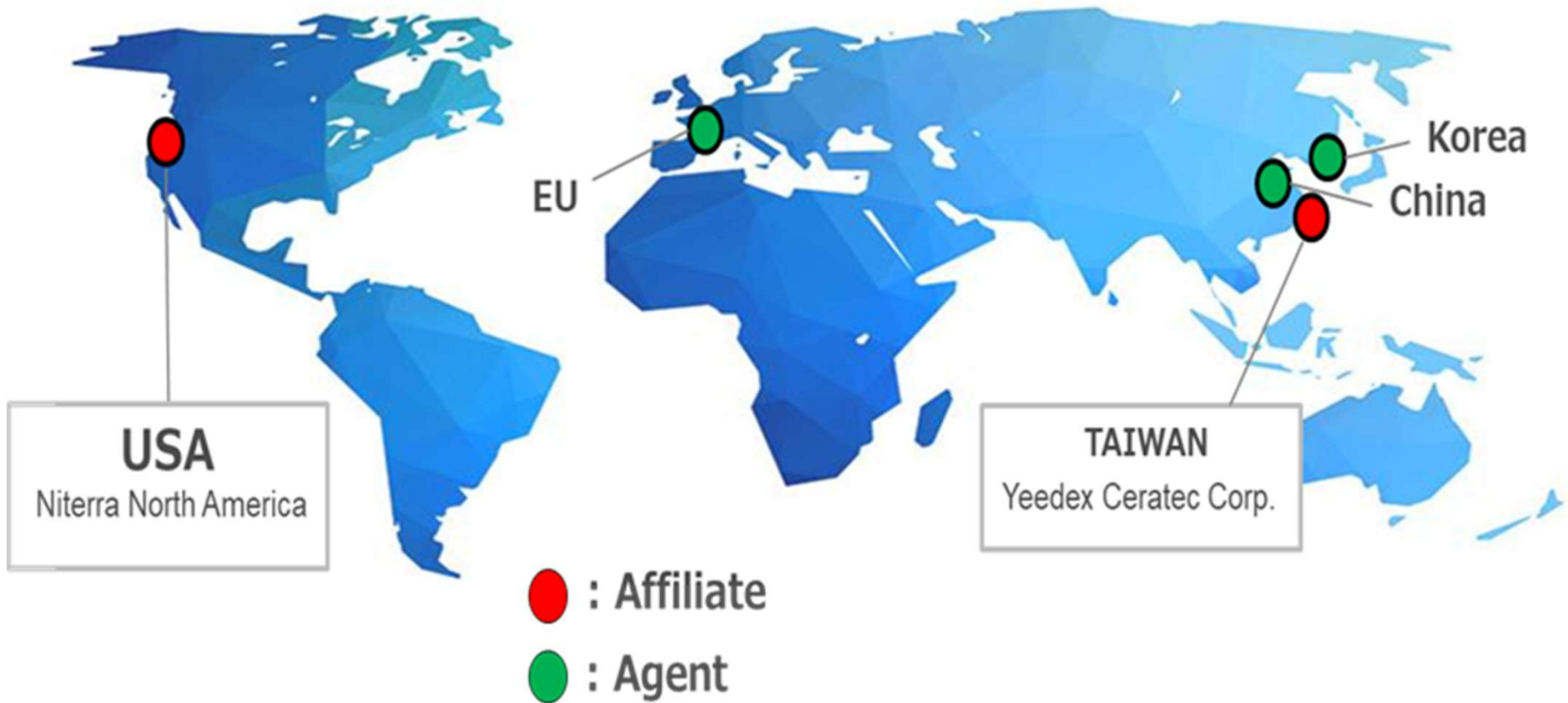


2026~  
Tomiya new factory  
(Under construction)



Komaki Fab  
2024~

# Location Oversea

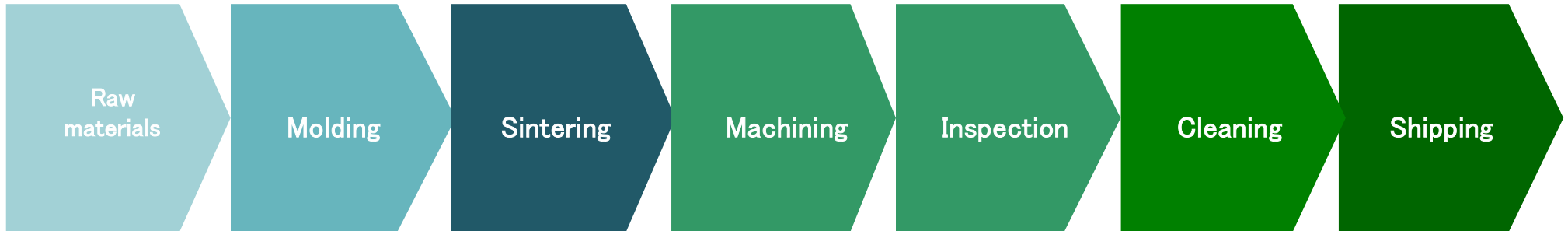


## Company Highlights

- ✓ End-to-End Manufacturing
- ✓ Innovative Material R&D
- ✓ Semiconductor-Centric Business

# End to End manufacturing

From raw material mixing to shipping in-house.



# Material line up - General

## NTK has a wide range of materials for various needs



**Al<sub>2</sub>O<sub>3</sub>** (Alumina): The most popular materials for fine ceramics, with relatively low manufacturing costs.



**ZrO<sub>2</sub>** (Zirconia): The highest mechanical strength and toughness



**SiC** (Silicon Carbide): High Strength in high temp, High thermal conductance, Corrosion resistance



**Si<sub>3</sub>N<sub>4</sub>** (Silicon Nitride): Low thermal expansion  
High temp toughness  
High thermal shock resistance



**AlN** (Aluminum Nitride): High Thermal Conductivity, Heater material



**Low Dielectric Loss Alumina:** Used for Semiconductor equipment



**Thermal Shock resistance alumina:**  
High toughness, Used for components around heater, etc



**High Purity Pore Free alumina:** Purity 99.99%, Plasma resistance  
Low Dielectric Loss



**Zero thermal expansion Pore Free ceramics (ZPF):**  
Pore Free, High stiffness



**Low thermal expansion insulating ceramics Adceram-CS®:**  
Low thermal expansion, High thermal shock resistance ,Low heat conductivity



**Machinable ceramics Macor®:**  
Processed easily, Manufactured faster, Heat resistance/insulating

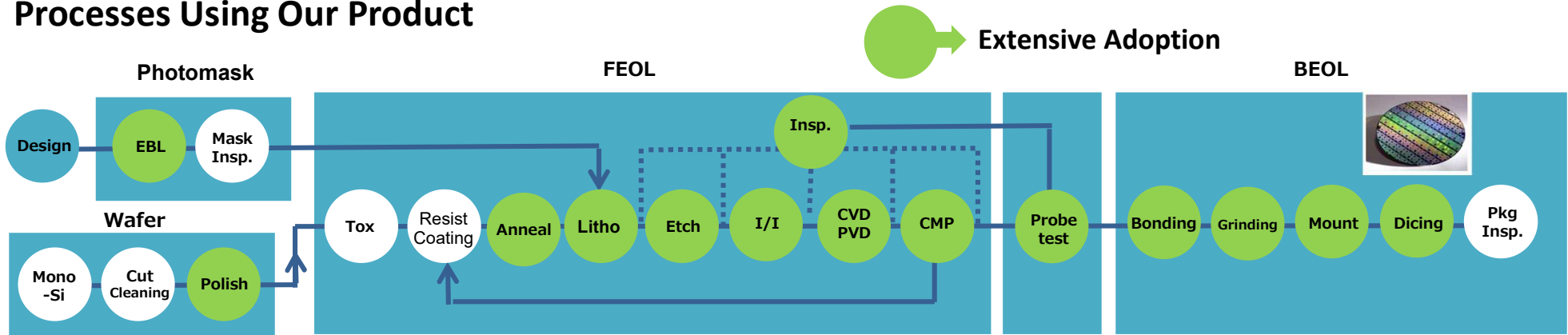
# Characteristics - NTK's General & *unique* materials

## ⇒ Unique ( NTK Original)


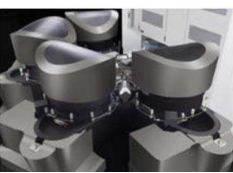




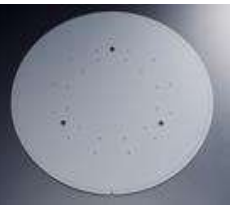



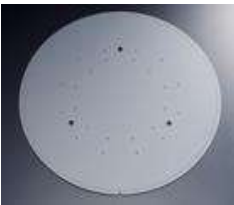

Material		Characteristics	Coefficient of thermal expansion	Thermal shock resistance	Coefficient of thermal conductivity	Electrical resistance	Dielectric strength	Dielectric constant	Dielectric loss
			$\times 10^{-6}/K$	K	W/m · K	$\Omega \cdot cm$	kV/mm		$\times 10^{-4}$
Alumina (Al <sub>2</sub> O <sub>3</sub> )	Standard product	A995	7.3	200	30	$>10^{14}$	12	10	<300
Alumina (Al <sub>2</sub> O <sub>3</sub> )	Low-dielectric loss type	A995LD	7.5	200	30	$>10^{14}$	12	10	<5
Alumina (Al <sub>2</sub> O <sub>3</sub> )	Thermal shock residence type	A995S	7.1	500	30	$>10^{14}$	-	10	<300
Zirconia (ZrO <sub>2</sub> )	Standard product	AYZ-3	10	280	3	$10^{12}$	>10	35	20
Silicon carbide (SiC)	Standard product	N-Type	4.6	450	170	$10^6$	-	-	-
Silicon nitride (Si <sub>3</sub> N <sub>4</sub> )	Standard product	ASN-5	2.3	700	26	$>10^{14}$	>10	8	3
Aluminum nitride (AlN)	Standard product	N-Type	4	400	160	$10^{14}$	>15	9	10
Zero thermal expansion Pore Free ceramics	ZPF	N-Type	-	-	5	$10^{12}$	-	-	-
Low thermal expansion insulating ceramics	Adceram-CS®	D3	0.9	700	1.3	$10^{10}$	20	7.5	35
Machinable ceramics Macor®	Macor®	-	9.3	150	1.7	$10^{16}$	40	6	50

# Usage of our products in semiconductor processes

## Processes Using Our Product



## Application example

 <p>Lith tool</p>	   <p>Etcher      CVD      Sputtering</p>			  <p>Inspection      Grinder/Mounter/Dicer</p>	
 <p>Wafer table</p>	   <p>Spray coating      ESC      ESC</p>			  <p>Wafer table      Porous Chuck</p>	

# Cleaning & Analysis system for Semiconductor

## Measurement

Laser interferometer (Zygo)



Non contact surface roughness meter



Non contact 3D optical Profilometer



## Cleaning and Analysis

In house cleaning



Liquid particle counter



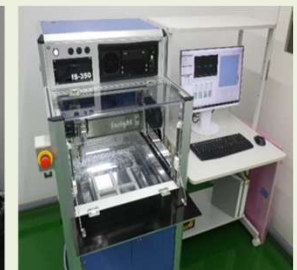
Particle counter



ICP-MS



C-SAM



# Market trend

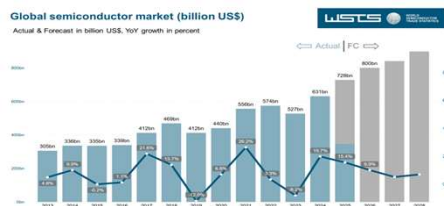
## Dec 2025 FCT

### Global semiconductor market (billion US\$)

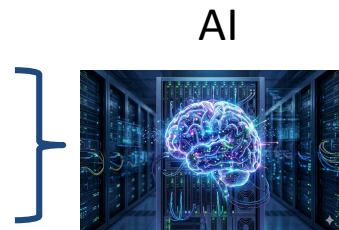
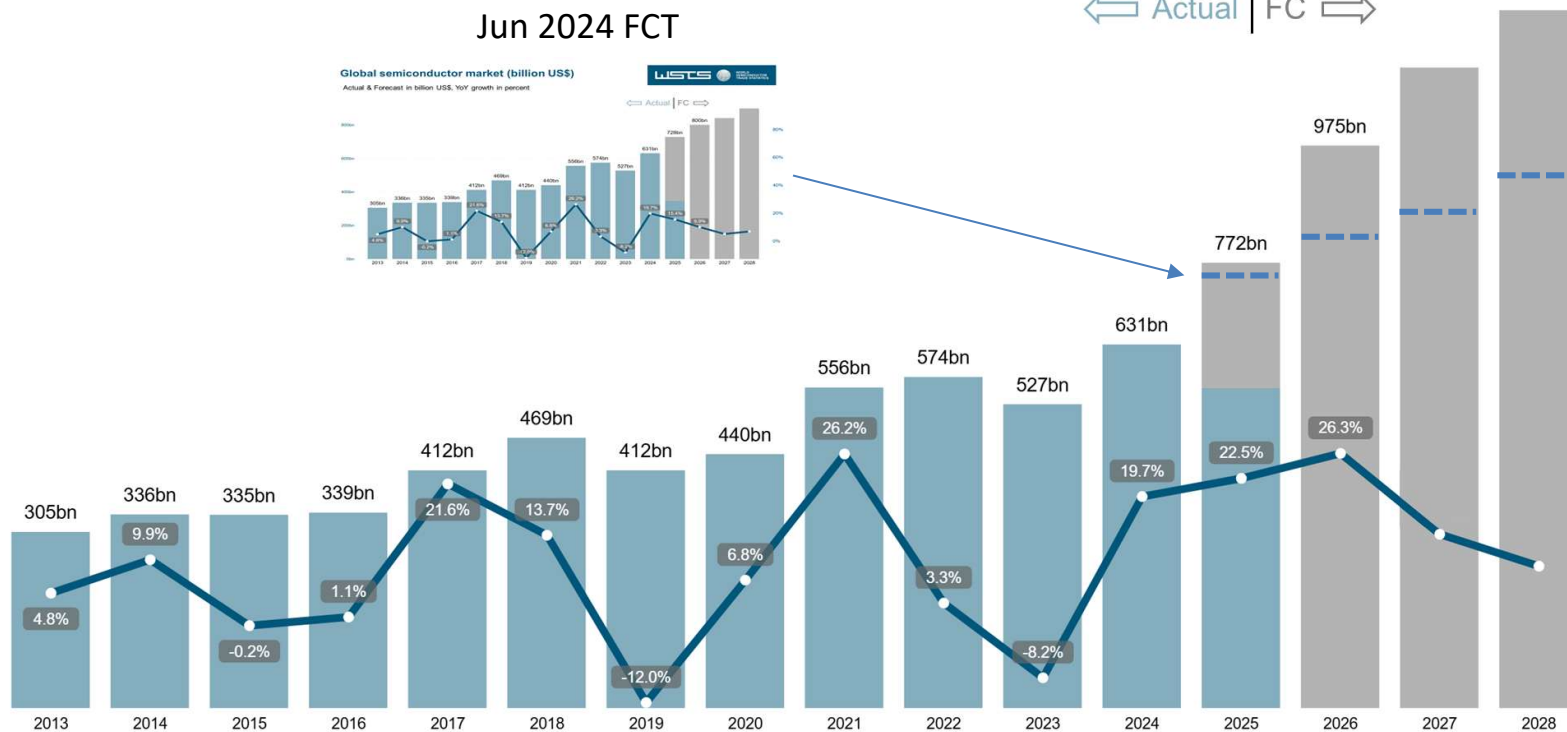


Actual & Forecast in billion US\$, YoY growth in percent

Jun 2024 FCT



Actual | FC



2026~



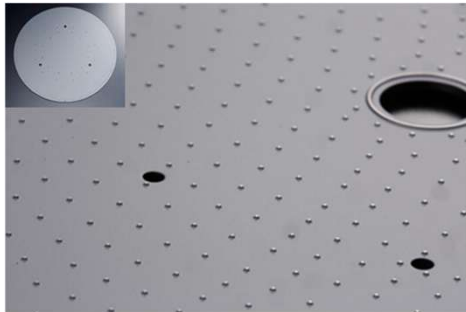
Tomiya new factory (Under construction)

Source: WSTS website

# Key products

## ✓ High-Performance Vacuum

**Ultra-Precision Wafer table**



**Adhesive-free porous wafer table**

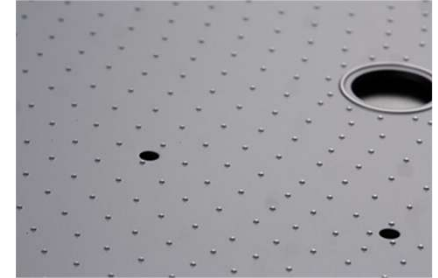


## Advanced Electrostatic Chucks (ESC)

**Design-Flexible Multilayer ESC**



# Ultra-Precision Wafer table

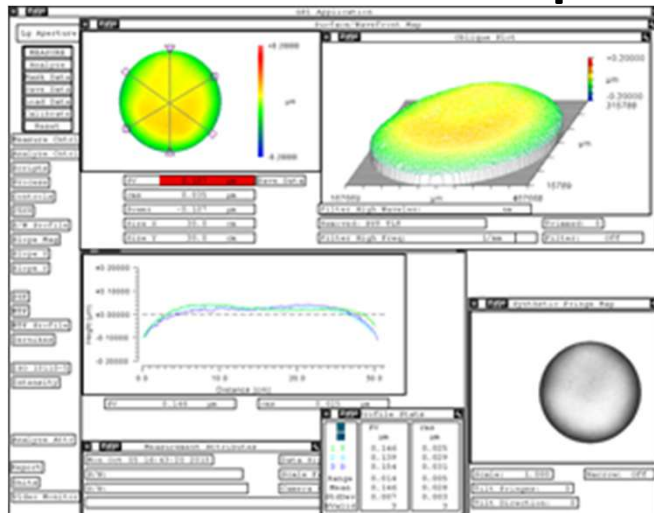


Process	Requirement	NCC Technology
Lithography	High precision	<ul style="list-style-type: none"> <li>• Ultimate flatness</li> <li>• Surface shape control</li> </ul>
Wafer inspection	Warpage wafer	<ul style="list-style-type: none"> <li>• Warped wafer chucking</li> </ul>
Wafer bonding	Low particle	<ul style="list-style-type: none"> <li>• Pin bottom polishing</li> <li>• Small diameter pin</li> </ul>
	Temp uniformity	<ul style="list-style-type: none"> <li>• Hollow structure</li> </ul>
	High cleanliness	<ul style="list-style-type: none"> <li>• Cleaning and Analysis</li> </ul>

# Ultra-Precision Wafer table Ultimate flatness



**Global Flatness  $\leq 0.3\mu\text{m}$**



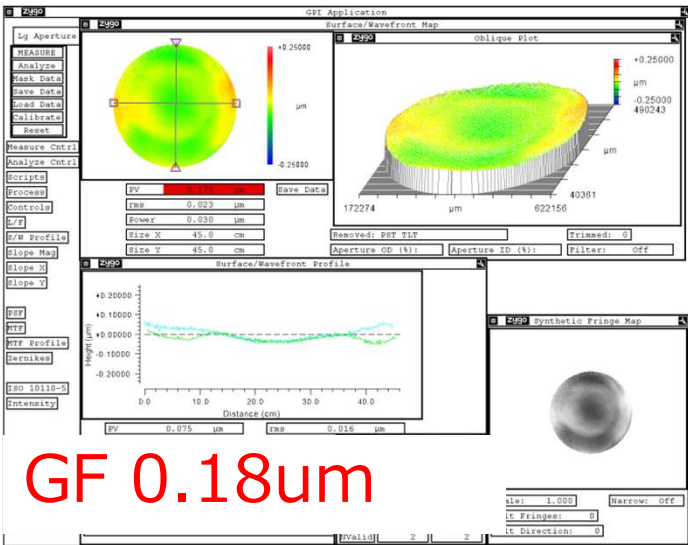
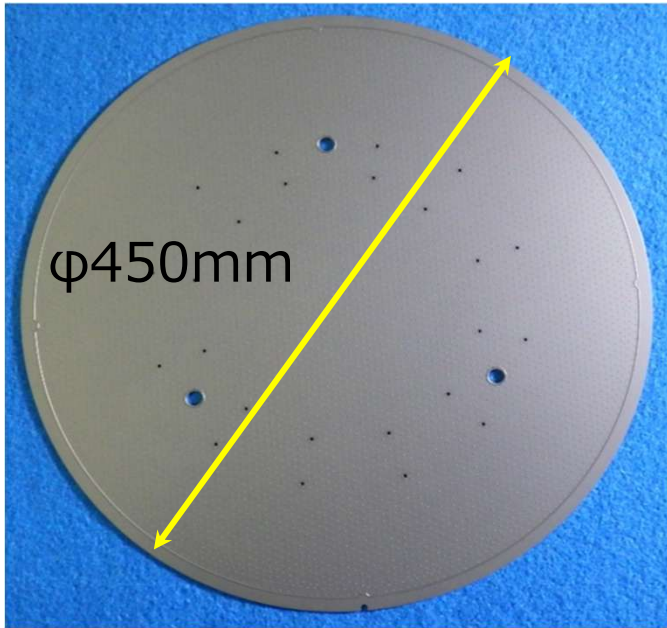
Global Flatness PV  $0.187\mu\text{m}$

**Local Flatness  $\leq 0.05\mu\text{m}$**

				0.009	0.014	0.014	0.025	0.027	0.013	0.012						
			0.008	0.015	0.015	0.008	0.013	0.012	0.015	0.016	0.028	0.018	0.009			
		0.011	0.015	0.023	0.011	0.011	0.015	0.016	0.012	0.011	0.012	0.015	0.014	0.008		
			0.017	0.012	0.012	0.018	0.015	0.016	0.023	0.015	0.011	0.012	0.014	0.014	0.035	
	0.01	0.021	0.011	0.013	0.011	0.011	0.012	0.011	0.012	0.013	0.011	0.015	0.012	0.021	0.015	
	0.012	0.011	0.011	0.012	0.022	0.017	0.014	0.018	0.011	0.016	0.015	0.013	0.011	0.014	0.02	
	0.017	0.013	0.013	0.009	0.011	0.014	0.016	0.024	0.019	0.013	0.012	0.011	0.018	0.012	0.027	
		0.024	0.018	0.015	0.009	0.008	0.011	0.016	0.024	0.017	0.013	0.012	0.011	0.013	0.012	0.013
		0.015	0.013	0.011	0.011	0.012	0.016	0.013	0.022	0.016	0.013	0.01	0.012	0.014	0.015	0.016
		0.016	0.012	0.021	0.016	0.015	0.01	0.016	0.01	0.012	0.012	0.013	0.019	0.013	0.013	0.012
		0.016	0.012	0.013	0.028	0.014	0.011	0.009	0.011	0.012	0.031	0.011	0.015	0.012	0.016	0.009
			0.03	0.018	0.017	0.013	0.012	0.009	0.013	0.011	0.012	0.009	0.013	0.015	0.017	
			0.01		0.026	0.023	0.013	0.012	0.012	0.013	0.011	0.011	0.011	0.015	0.025	0.007
				0.007		0.02	0.019	0.018	0.012	0.012	0.012	0.016	0.018	0.024	0.009	
								0.009	0.027	0.03	0.029	0.037	0.022	0.011		

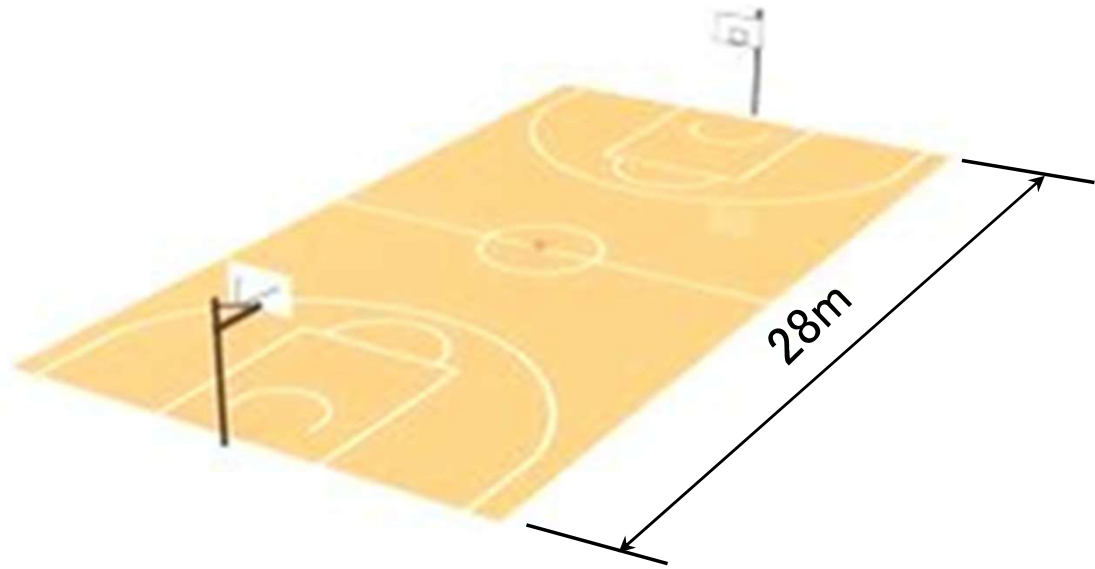
Local Flatness Ave  $0.015\mu\text{m}$  Max  $0.037\mu\text{m}$

# Ultra-Precision Wafer table Ultimate flatness



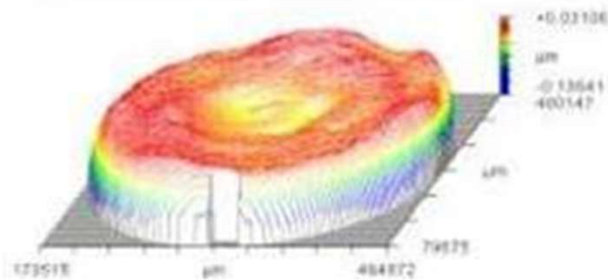
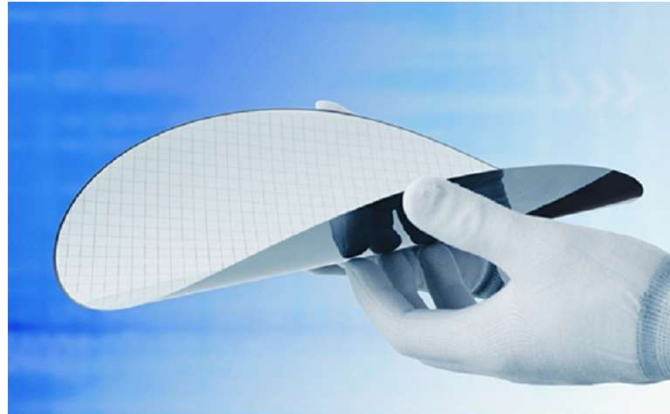
Like  
➔

Basketball court...

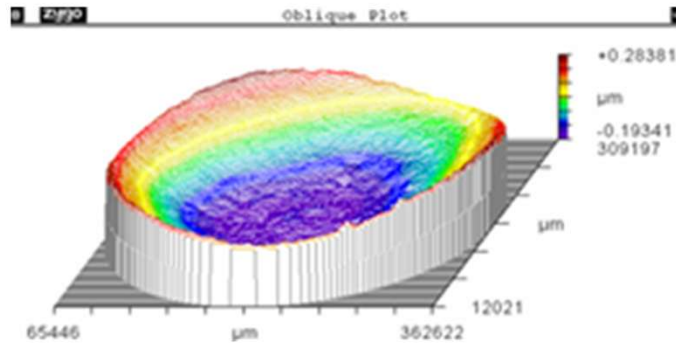


凸凹0.01mm/28m

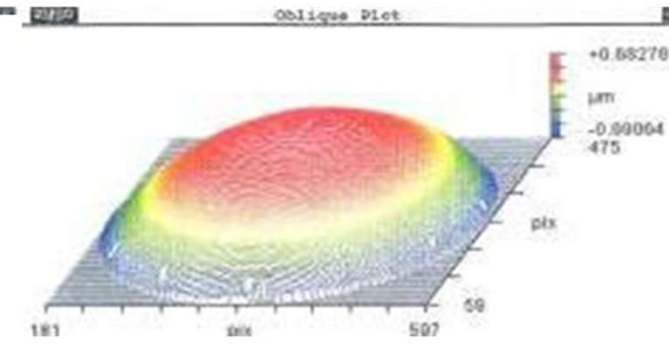
# Ultra-Precision Wafer table Surface shape control



Flat  
flatness 0.16 $\mu\text{m}$

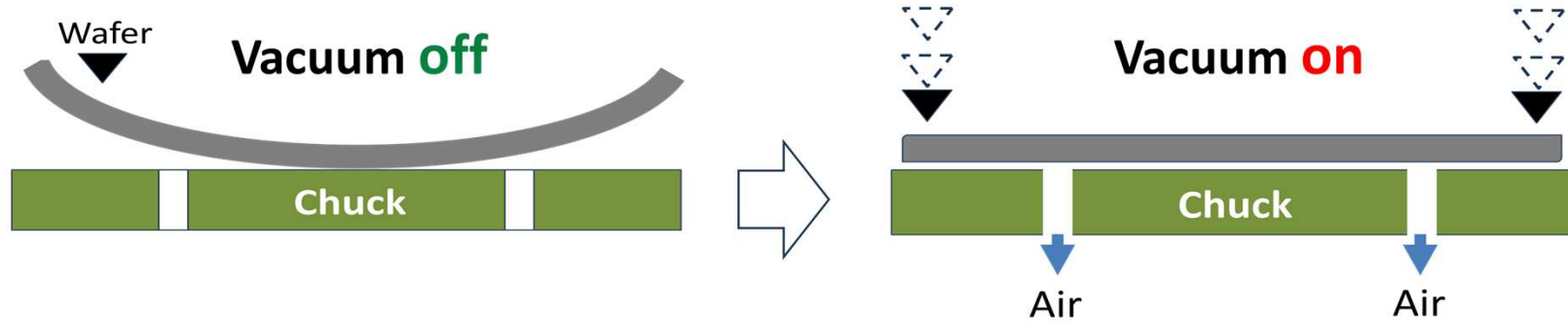


Concave  
flatness 0.48 $\mu\text{m}$



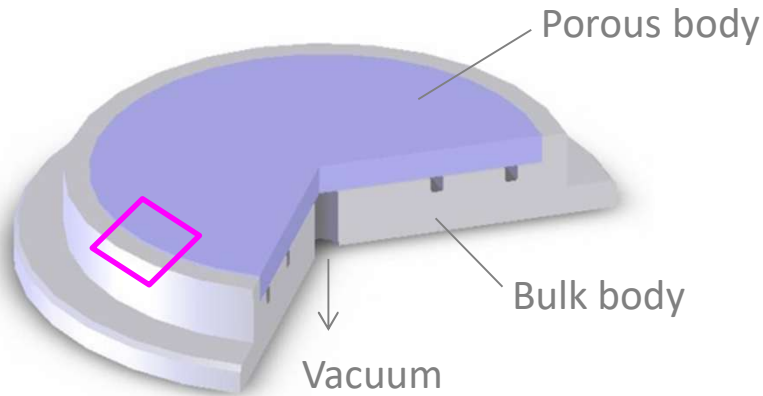
Convex  
flatness 0.56 $\mu\text{m}$

# Ultra-Precision Wafer table Warped wafer chucking



Warpage : 3mm

# Porous chuck – Adhesive free



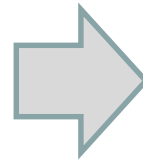
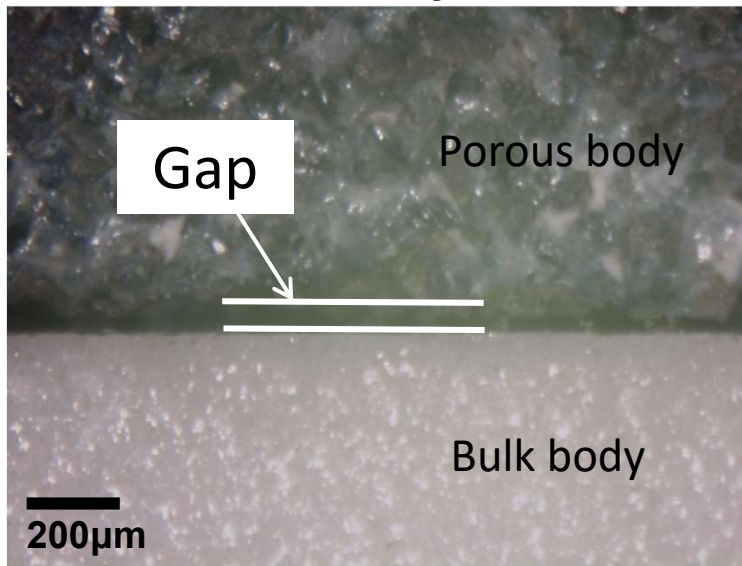
STD SPEC

Pore size : 30 $\mu$ m

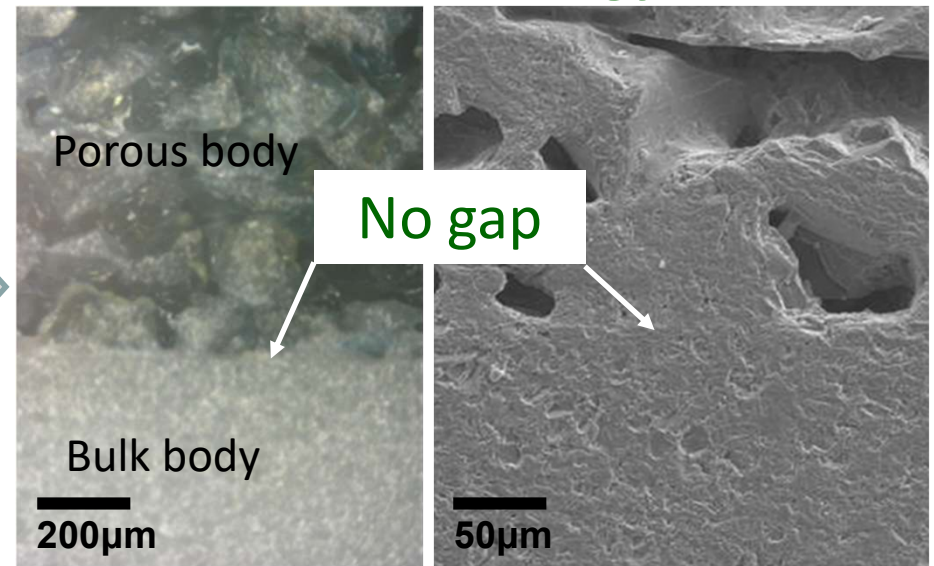
Porosity : 35%

Flatness : 5 $\mu$ m

## Connected by ashesive



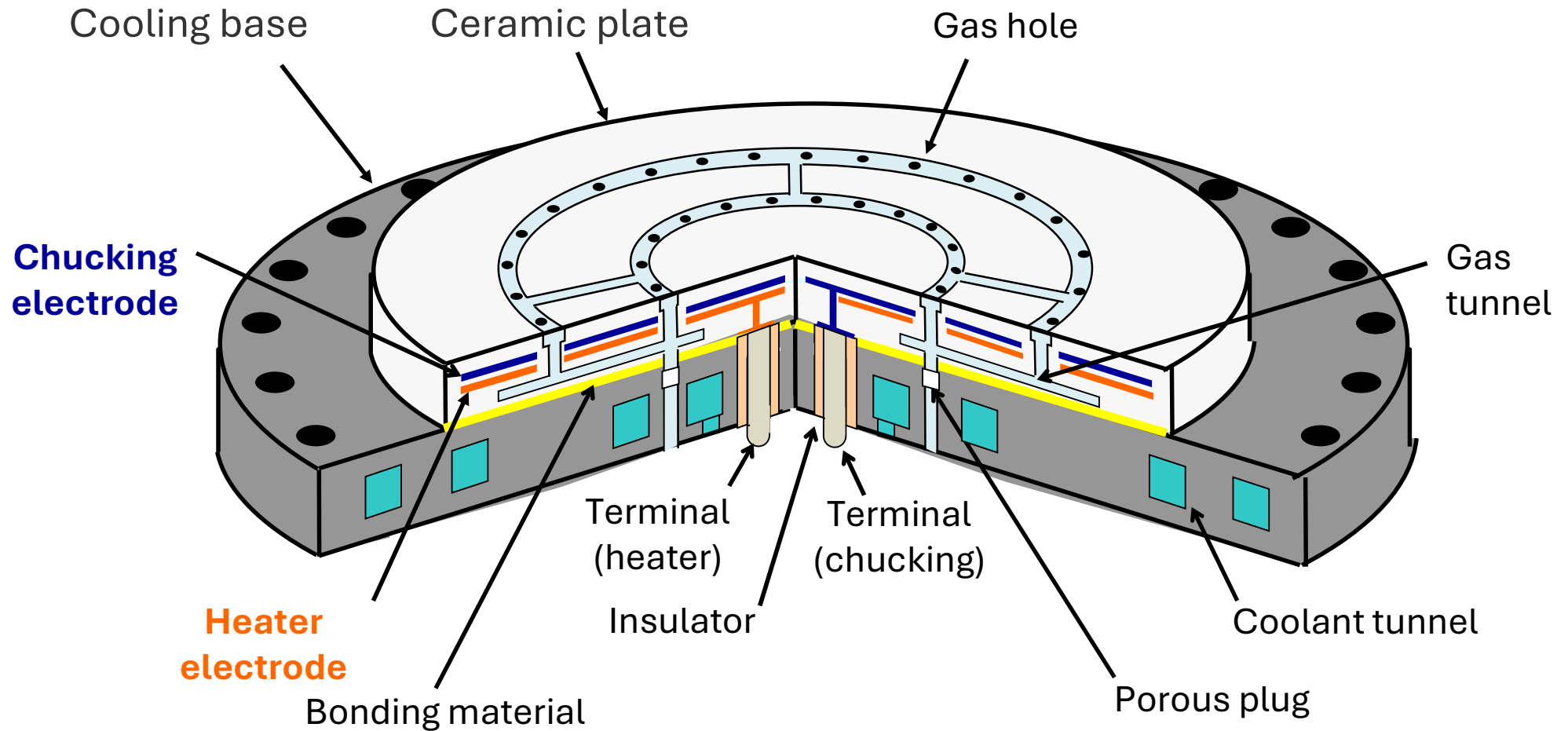
## NTK Technology



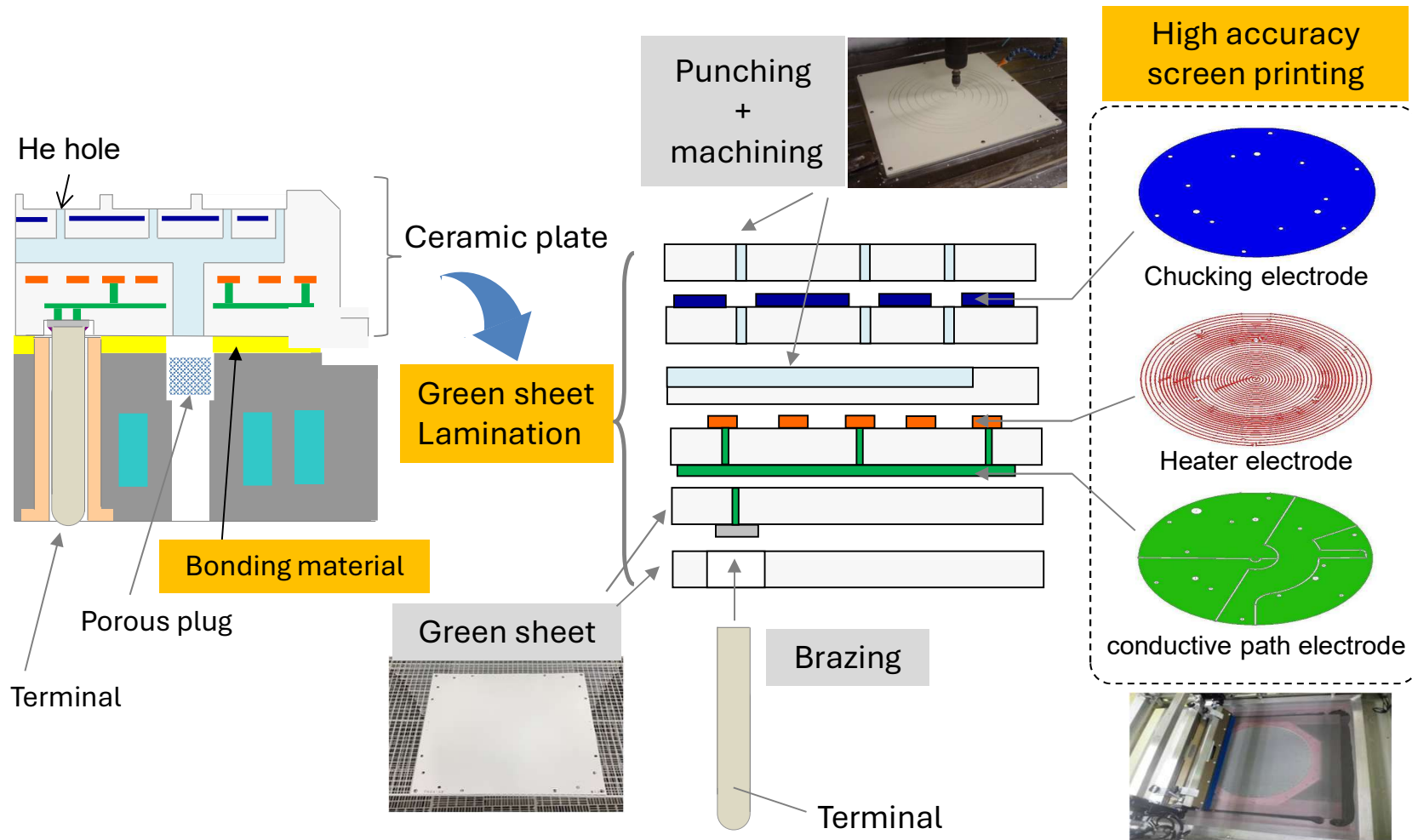
## Design-Flexible Multilayer ESC



# ESC (Laminated) - Fundamental design



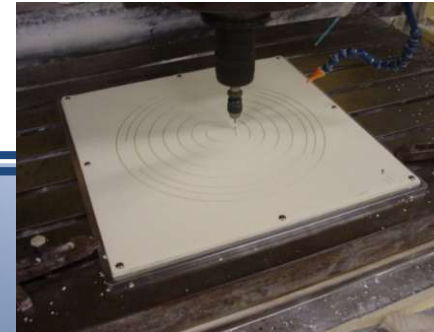
# ESC (Laminated) – Manufacturing technology



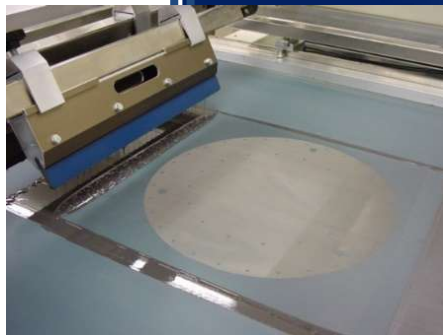
## Lamination



## Machining



High  
Flexibility  
In Design



High accuracy  
Screen printing



Bonding

# Thank you

ありがとうございました。

